

Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

Jenihhin, Maksim; Squillero, Giovanni; **Tihomirov, Valentin**; **Kostin, Sergei**; **Raik, Jaan**; **Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <http://dx.doi.org/10.1007/s10836-016-5589-x>

On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks

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Post-silicon validation of IEEE 1687 reconfigurable scan networks

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Rejuvenation of NBTI-impacted processors using evolutionary generation of assembler programs

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